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(54) VECTOR SET GENERATION METHOD, TESTING SYSTEM, AND RECORDING MEDIUM FOR STORING TEST PROGRAM

compressed vector sets, one vector set is prepared.

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(57) Abstract:

PROBLEM TO BE SOLVED: To provide a method for generating a vector set that is used for testing a sequential circuit.

SOLUTION: The method is used to select a plurality of fault models. Each fault list is identified for each of a plurality of fault models. Each vector set is identified for each of the fault lists. Each allowed limit value is selected for each of the fault lists, thus enabling each fault model to have each related fault list, related vector set, and related allowable limit value. Each of the above vector sets is compressed so that an already compressed vector set identifies all faults in the related failure set or the decrease in the fault list coverage stays within the range of the related allowable limit value. Also, by connecting all

